Search Notes		
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Application/Control No.	Applicant(s)/Patent under Reexamination	•
10/600,145	LEE ET AL.	
Examiner	Art Unit	
N M Minnifield	1645	

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NO' (INCLUDING SEARCH)
	DATE	EXMR
see attached, WEST, NPL, PALM, STN, related applications	3/6/2006	NMM